

SIGC18T60NC

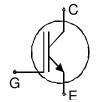
IGBT Chip in NPT-technology

FEATURES:

- 600V NPT technology
- 100µm chip
- positive temperature coefficient
- easy paralleling

This chip is used for:

IGBT Modules



Applications:

• drives

Chip Type	V _{CE}	I _{Cn}	Die Size	Package	Ordering Code
SIGC18T60NC	600V	20A	4.3 x 4.3 mm ²	sawn on foil	Q67050-A4139-
0.0.0.0.00.00		_0,1		oawn on ion	A001

MECHANICAL PARAMETER:

Raster size	4.3 x 4.3			
Area total / active	18.49 / 14.3			
Emitter pad size	2.48 x 2.98			
Gate pad size	0.7 x 1.08			
Thickness	100	μm		
Wafer size	150	mm		
Flat position	270	deg		
Max.possible chips per wafer	796			
Passivation frontside	Photoimide			
Emitter metallization	3200 nm Al Si 1%			
Collector metallization	1400 nm Ni Ag -system suitable for epoxy and soft solder die bonding			
Die bond	electrically conductive glue or solder			
Wire bond	AI, ≤500μm			
Reject Ink Dot Size	Ø 0.65mm ; max 1.2mm			
Recommended Storage Environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C			



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MAXIMUM RATINGS:

Parameter	Symbol	Value	Unit
Collector-emitter voltage, T_j =25 °C	V _{CE}	600	V
DC collector current, limited by T _{jmax}	I _C	1)	Α
Pulsed collector current, t _p limited by T _{jmax}	I _{cpuls}	60	Α
Gate emitter voltage	V _{GE}	±20	V
Operating junction and storage temperature	T_j , T_{stg}	-55 + 150	°C

¹⁾ depending on thermal properties of assembly

STATIC CHARACTERISTICS (tested on chip), T_j =25 °C, unless otherwise specified:

Parameter	Symbol	Conditions	Value			Unit
- arameter			min.	typ.	max.	
Collector-emitter breakdown voltage	$V_{(BR)CES}$	$V_{GE}=0V$, $I_{C}=1mA$	600			
Collector-emitter saturation voltage	V _{CE(sat)}	V_{GE} =15V, I_{C} =20A	1.7	2.0	2.5	V
Gate-emitter threshold voltage	$V_{GE(th)}$	$I_C=0.5mA, V_{GE}=V_{CE}$	4.5	5.5	6.5	
Zero gate voltage collector current	I _{CES}	V _{CE} =600V, V _{GE} =0V			1.5	μΑ
Gate-emitter leakage current	I _{GES}	$V_{CE}=0V, V_{GE}=20V$			120	nA

DYNAMIC CHARACTERISTICS (tested at component):

Parameter	Symbol	Conditions	Value			Unit
raiametei	Symbol		min.	typ.	max.	Joint
Input capacitance	Ciss	V _{CE} =25V	-	900	-	pF
Output capacitance	Coss	$V_{GE}=0V$	-	tbd	-	
Reverse transfer capacitance	C_{rss}	f=1MHz	-	80	-	

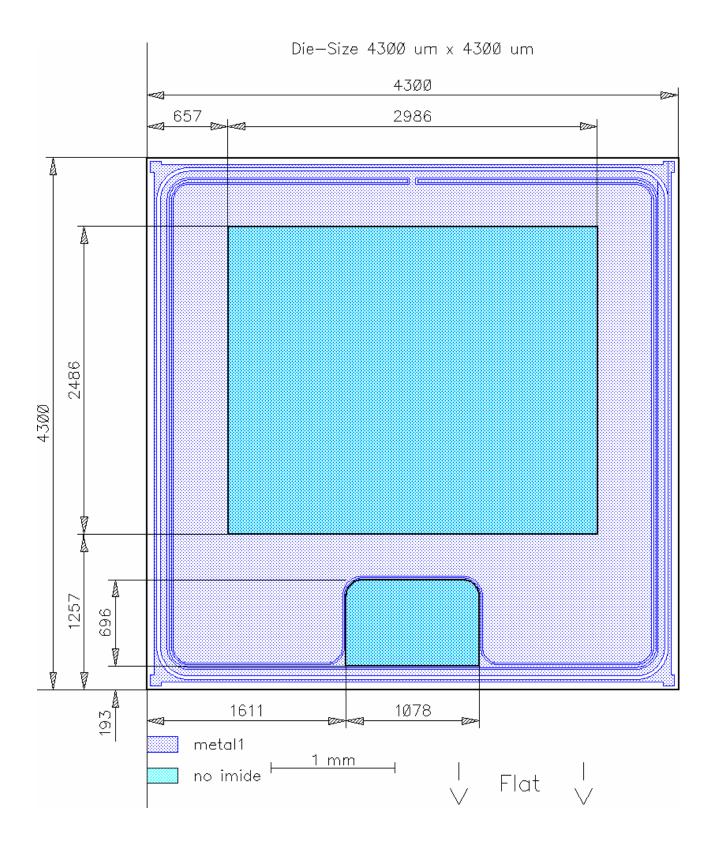
SWITCHING CHARACTERISTICS (tested at component), Inductive Load:

Parameter	Symbol	Conditions 1)	Value			Unit
raiametei			min.	typ.	max.	Oilit
Turn-on delay time	$t_{d(on)}$	$T_{\rm j} = 125 ^{\circ} ^$	-	21	-	ns
Rise time	t _r	I _C =20A	-	8	-	
Turn-off delay time	$t_{d(off)}$	$V_{\text{GE}} = \pm 15 \text{V}$ $R_{\text{G}} = 13 \Omega$	-	110	-	
Fall time	t_{f}	//G- 1032	-	25	-	

¹⁾ values also influenced by parasitic L- and C- in measurement and package.



CHIP DRAWING:





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FURTHER ELECTRICAL CHARACTERISTICS:

This chip data sheet refers to the device data sheet

FS 20 R06 XL4

Description:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

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